Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/747,948	HASEBE ET AL.	
Examiner	Art Unit	
IOHNI DAK	1616	

	SEAR	CHED	
Class	Subclass	Date	Examiner
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Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Inventor names seasched	3/06	M	